

Search Notes

Application/Control No.

10/823,469

Examiner

Lan Nguyen

Applicant(s)/Patent under
Reexamination

NAIK ET AL.

Art Unit

3683

SEARCHED

Class	Subclass	Date	Examiner
303	122.07	9/23/05	XLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
TEXT search included	9/23/05	XLN